

**Notice of References Cited**Application/Control No.  
**09/643,647**Inventor(s)/Patent Under Reexam  
**Dimeo et al.**Examiner  
**Rafael Perez-Gutierrez**Art Unit  
**2686**

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**U.S. PATENT DOCUMENTS**

	<b>Document Number</b> Country Code-Number-Kind Code	<b>Date</b> MM-YYYY <sup>1</sup>	<b>Name</b>	<b>Classification</b> <sup>2</sup>	
<b>A</b>	5,758,296	5/1998	Nakamura	455	307
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**FOREIGN PATENT DOCUMENTS**

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<b>N</b>						
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**NON-PATENT DOCUMENTS**

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